

Search Notes

Application/Control No.

10/784,164

Examiner

Seyed Azarian

Applicant(s)/Patent under
Reexamination

NIWA ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
382	103,106 107,117	4/12/2007	S.A
382	118,154	4/12/2007	S.A
382	168,181	4/12/2007	S.A
382	203,232	4/12/2007	S.A
382	274,276	4/12/2007	S.A
382	285,291	4/12/2007	S.A
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348	419	4/12/2007	S.A
433	24	4/12/2007	S.A

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTOR SEARCH	4/12/2007	S.A
EAST SEARCH	4/12/2007	S.A
IEEE/NPL SEARCH	4/12/2007	S.A